## Sparch Notes

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Applicant(s)/Patent Under Reexamination 10575863 HAYNES ET AL.

Examiner

Art Unit

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3633

## SEARCHED

Class	Subclass	Date	Examiner
52	408, 409, 410, 411, 464, 461, 745.21, 746.1, 698	1/24/2010	BP
428	76, 412, 423.3, 423.7, 424.7, 424.2, 424.4, 424.7, 424.8, 425.8	3/15/2010	BP
411	531, 480	3/15/2010	BP

## **SEARCH NOTES**

Search Notes	Date	Examiner
Consulted Primary Examiner Brian Glessner (Class 52) for search help	1/24/2010	BP
Consulted Primary Examiner Alex Thomas (Class 428) for search help	3/15/2010	BP
Consulted Primary Examiner Flemming Saether (Class 411) for search help	3/15/2010	BP
Consulted Primary Examiner Dhirajlal Nakarani (Class 428) for search help	3/15/2010	BP
Please see EAST search history for text searches	4/8/2010	BP

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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